

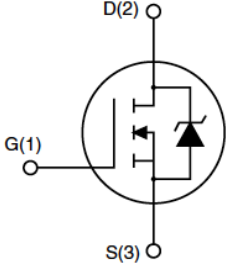


Description

<p>Features</p> <ul style="list-style-type: none"> ● 600V, 1.3A ● $R_{DS(ON)} = 8.5\Omega$ (Typ.) @ $V_{GS} = 10V, I_D = 0.65A$ ● Fast Switching ● Improved dv/dt Capability ● 100% Avalanche Tested 	<p>Application</p> <ul style="list-style-type: none"> ● Switch Mode Power Supply(SMPS) ● Uninterruptible Power Supply(UPS) ● Power Factor Correction(PFC) 	
 <p>TO-252</p>	 <p>TO-251</p>	 <p>Schematic Diagram</p>

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Max.	Units
V_{DSS}	Drain-Source Voltage	600	V
V_{GSS}	Gate-Source Voltage	± 30	V
I_D	Continuous Drain Current	$T_C = 25^\circ\text{C}$	1.3
		$T_C = 100^\circ\text{C}$	0.8
I_{DM}	Pulsed Drain Current ^{note1}	4	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}	20	mJ
dv/dt	Peak Diode Recovery Energy	5	V/ns
P_D	Power Dissipation	$T_C = 25^\circ\text{C}$	45
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2.8	$^\circ\text{C}/\text{W}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

*Drain current limited by maximum junction temperature

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	600	-	-	V
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to 25°C , $I_D=250\mu A$	-	0.6	-	$V/^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 600V, V_{GS} = 0V,$ $T_J = 25^\circ\text{C}$	-	-	1	μA
		$V_{DS} = 480V, V_{GS} = 0V,$ $T_J = 125^\circ\text{C}$	-	-	10	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 30V$	-	-	± 100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	3.0	4.0	V
$R_{DS(on)}$	Static Drain-Source on-Resistance <small>note3</small>	$V_{GS} = 10V, I_D = 0.65A$	-	8.5	10	Ω
g_{FS}	Forward Transconductance	$V_{DS} = 40V, I_D = 0.65A$	-	0.9	-	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS} = 25V, V_{GS} = 0V,$ $f = 1.0\text{MHz}$	105	-	160	pF
C_{oss}	Output Capacitance		18.8	-	28.2	pF
C_{rss}	Reverse Transfer Capacitance		2.8	-	4.5	pF
Q_g	Total Gate Charge	$V_{DS} = 480V, I_D = 1A,$ $V_{GS} = 10V$	-	6.1	8	nC
Q_{gs}	Gate-Source Charge		-	1.3	2	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	3.1	4	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DS} = 300V, I_D = 1A,$ $R_G = 25\Omega$	-	10	13	ns
t_r	Turn-on Rise Time		-	10	18	ns
$t_{d(off)}$	Turn-off Delay Time		-	20	26	ns
t_f	Turn-off Fall Time		-	11.5	23	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current		-	-	1	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	4	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 1A$	-	0.82	1	V
t_{rr}	Reverse Recovery Time	$V_{DS} = 100V, I_F = 1.3A,$ $di/dt = 100A/\mu s$	-	114	137	ns
Q_{rr}	Reverse Recovery Charge		-	0.63	0.76	μC

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

 2. $L=60\text{mH}, I_{AS} = 1A, V_{DD} = 150V, R_G = 10 \Omega$, starting $T_J = 25^\circ\text{C}$

 3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 1\%$

Typical Performance Characteristics

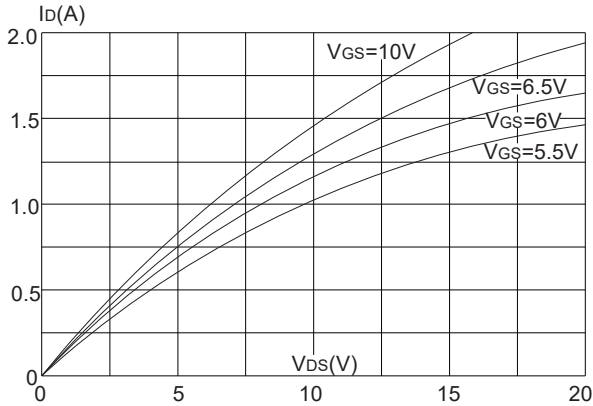
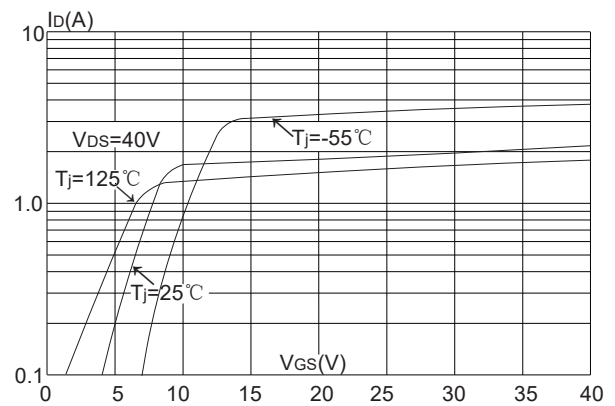
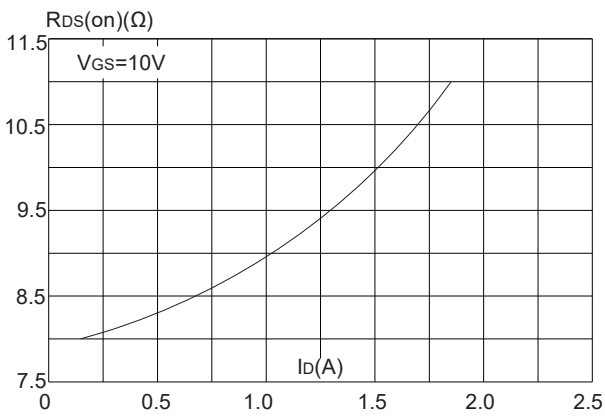
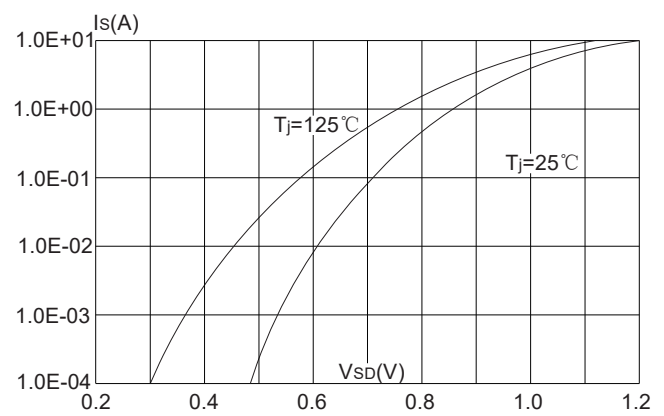
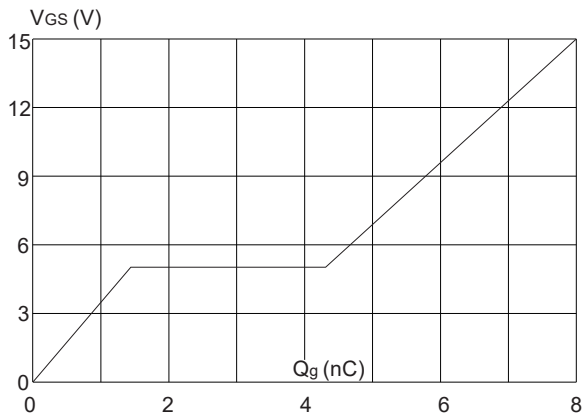
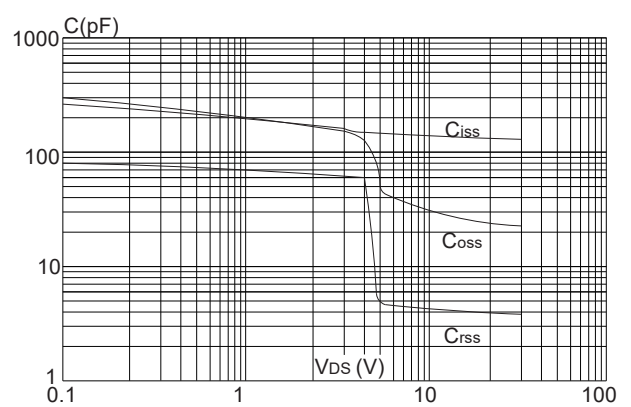
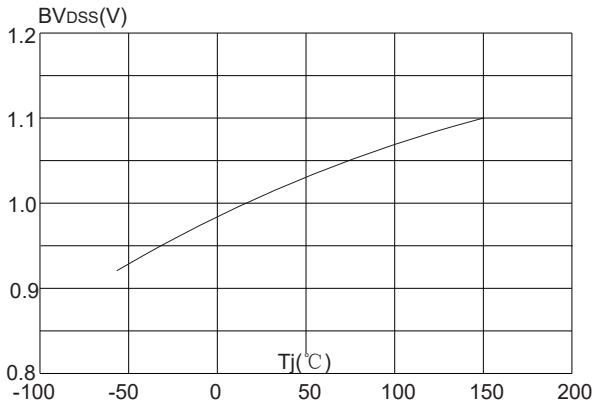
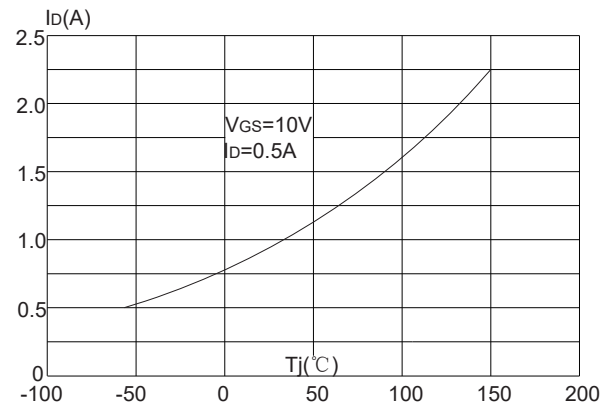
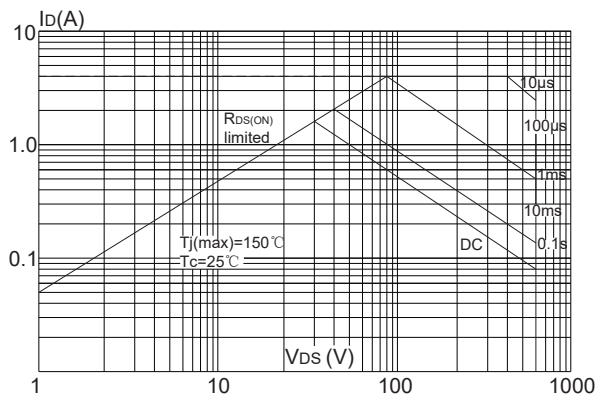
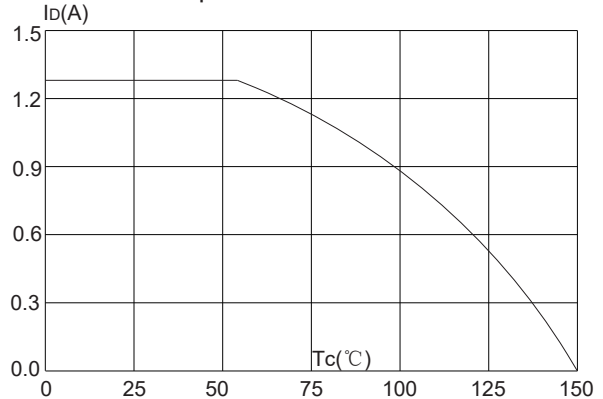
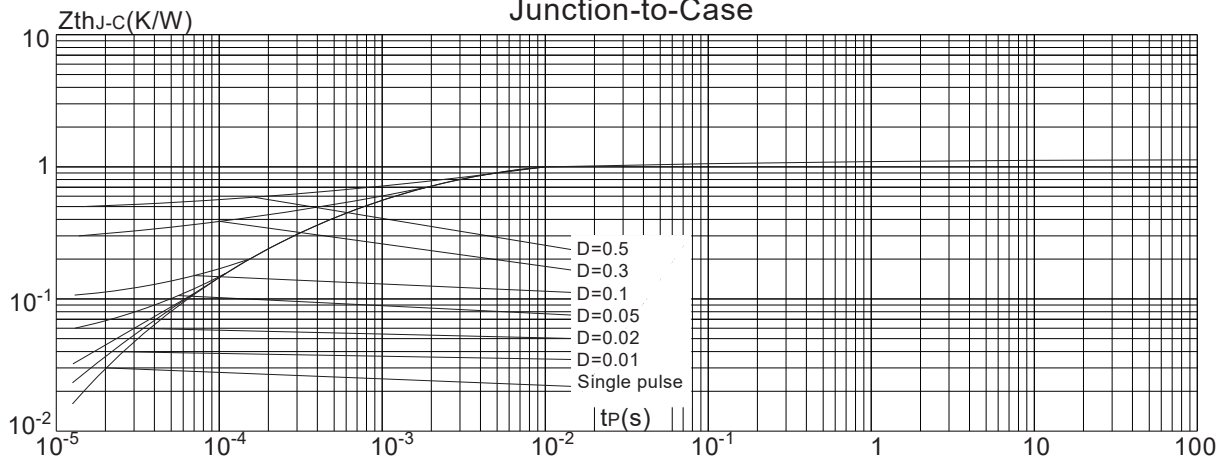
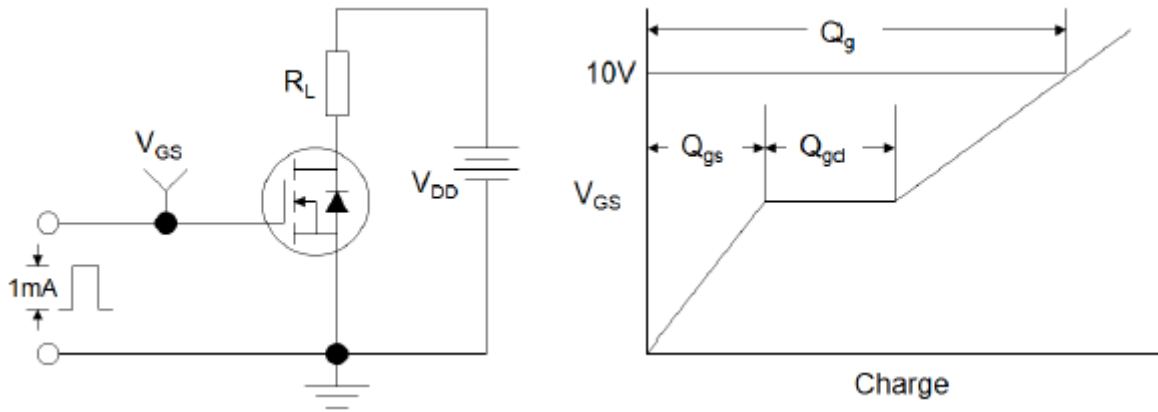
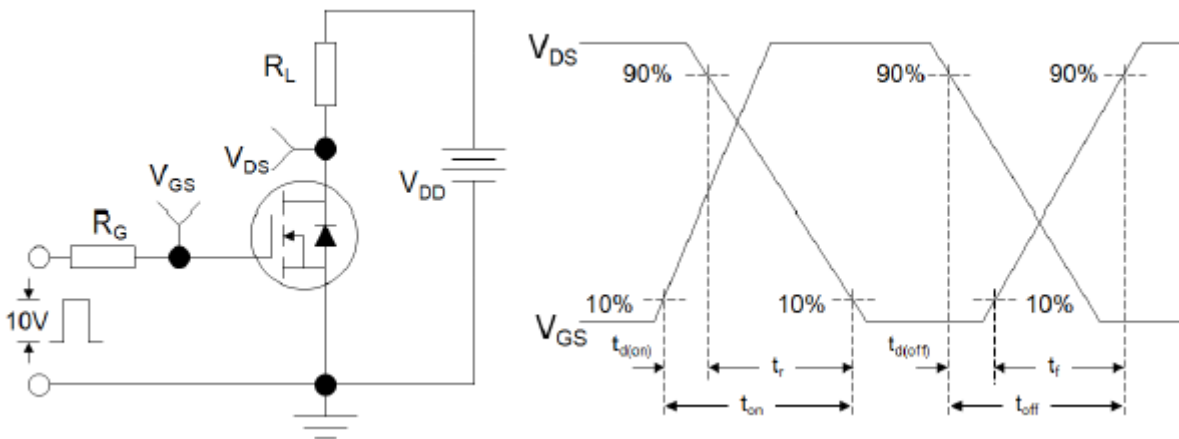
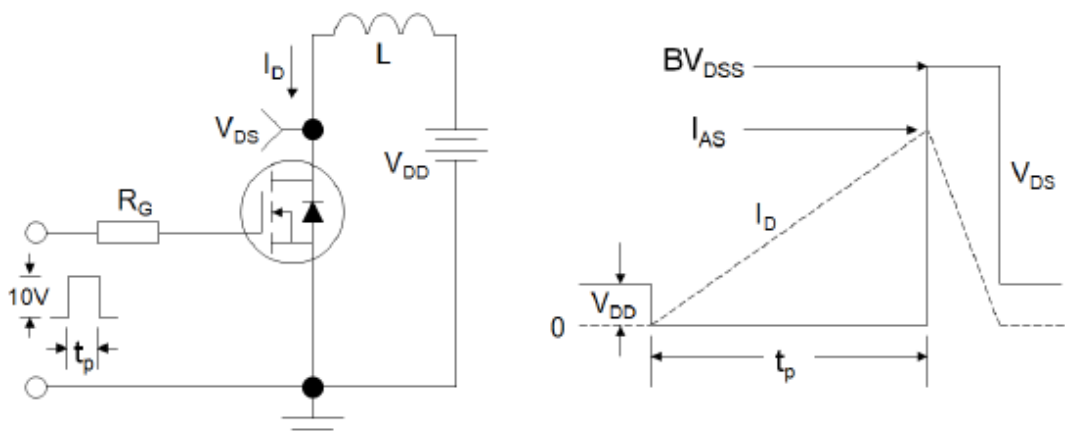
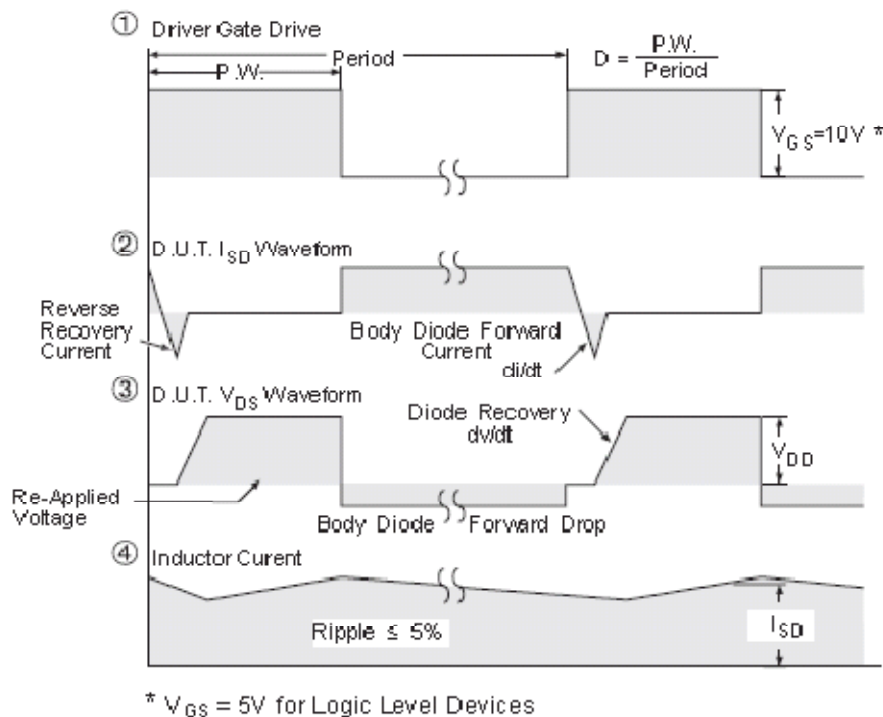
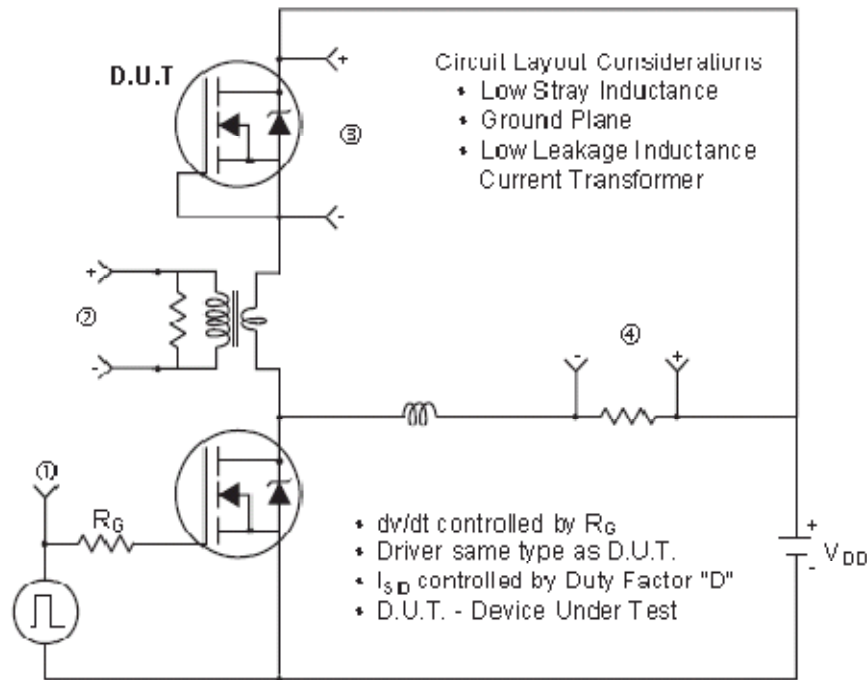
Figure 1: Output Characteristics

Figure 2: Typical Transfer Characteristics

Figure 3: On-resistance vs Drain Current

Figure 4: Body-Diode Characteristics

Figure 5: Gate Charge Characteristics

Figure 6: Capacitance Characteristics


Figure 7: Breakdown Voltage vs Junction Temperature

Figure 8: On-Resistance vs Junction Temperature

Figure 9: Maximum Safe Operating Area

Figure 10: Maximum Continuous Drain Current vs. Case Temperature

Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



Figure12:Gate Charge Test Circuit & Waveform

Figure 13: Resistive Switching Test Circuit & Waveforms

Figure 14:Unclamped Inductive Switching Test Circuit & Waveforms


Figure 15: Peak Diode Recovery dv/dt Test Circuit & Waveforms (For N-channel)